ATS19520

Vibration-Tolerant Hall-Effect Transmission Speed and Direction Gear Tooth Sensor IC

FEATURES AND BENEFITS DESCRIPTION

- **Differential Hall-effect sensor** measures ferrous targets with inherent stray field immunity
- **SolidSpeed Digital Architecture** provides robust, adaptive performance with advanced algorithms that provide vibration immunity over the full target pitch
- **Integrated solution** includes a back-bias magnet and capacitor in a single overmolded package
- **ISO 26262 ASIL B** with integrated diagnostics and certified safety design process
- **Two-wire current source output** pulse-width protocol supporting speed, direction, and ASIL error reporting
- **EEPROM** enables factory traceability

PACKAGE: 3-pin SIP (suffix SN)

The ATS19520 is an advanced Hall-effect integrated circuit (IC) that uses an integrated back-bias magnet to measure the speed and direction of rotating ferrous targets. The package features an integrated capacitor for electromagnetic compatibility (EMC).

The ATS19520 employs intelligent algorithms that allow stable operation during vibration and highly dynamic air gap environments common to transmission applications. In addition, the differential sensing offers inherent rejection of interfering common-mode magnetic fields.

The ATS19520 was developed in accordance with ISO 26262 as a hardware safety element out of context with ASIL B capability for use in automotive safety-related systems when integrated and used in the manner prescribed in the applicable safety manual and datasheet.

The ATS19520 is provided in a 3-pin SIP package (suffix SN) that is lead (Pb) free, with tin leadframe plating. The SN package includes an IC, magnet, and capacitor integrated into a single overmold, with an additional molded lead-stabilizing bar for robust shipping and ease of assembly.

Functional Block Diagram

SELECTION GUIDE*

* Not all combinations are available. Contact Allegro sales for availability and pricing of custom programming options.

SPECIFICATIONS

ABSOLUTE MAXIMUM RATINGS

PINOUT DIAGRAM AND TERMINAL LIST

Terminal List Table

Number Name Name Function

1 | VCC | Supply voltage 2 | VCC | Supply voltage

Package SN, 3-Pin SIP Pinout Diagram

Internal Discrete Capacitor Ratings

Figure 1: Typical Application Circuit

OPERATING CHARACTERISTICS: Valid throughout full operating and temperature ranges, unless otherwise specified

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OPERATING CHARACTERISTICS (continued): Valid throughout full operating temperature ranges,

unless otherwise specified

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^[1] Typical values are at T_A = 25°C and V_{CC} = 12 V. Performance may vary for individual units, within the specified maximum and minimum limits.

[2] Maximum voltage must be adjusted for power dissipation and junction temperature; see representative for Power Derating discussions.

[3] Negative current is defined as conventional current coming out of (sourced from) the specified device terminal.

 $[4]$ Output transients prior to t_{PO} should be ignored.

[5] Timing from start of rising output transition. Measured pulse width will vary on load circuit configurations and thresholds. Pulse width measured at threshold of (I_{CC/HIGH)} + I $_{\rm CC(LOW)}$) / 2 for non-ASIL pulses and (I $_{\rm RESET}$ + I $_{\rm CC(LOW)}$) / 2 for ASIL pulses.

[6] Maximum Operating Frequency is determined by satisfactory separation of output pulses. If shorter low-state durations can be resolved, the maximum f_{REV} and f_{ND} may be higher. Does not appy to -xxIxxxx variant or f_{FWD}.

[7] Direction information is not available when frequency > f_{HIGH} for the Intermediate Pulse Width option.

[8] Zero-speed is not met when the xxxxxxK-variant is implemented due to the inclusion of a timed reset.

[9] Speed-related effects on maximum air gap are highly dependent upon specific target geometry. Consult with Allegro field applications engineering for aid with assessment of target geometries.

[10] Additional thermal information is available on the Allegro website.

 B_{DIFF} = The differential magnetic flux density sensed by the sensor.

Figure 3: Definition of T_{CYCLE}

Figure 4: Definition of Switch Point Separation

Reference Target 60-0 (60 Tooth Target)

FUNCTIONAL DESCRIPTION

Sensing Technology

The sensor IC contains a single-chip Hall-effect circuit that supports a trio of Hall elements. These are used in differential pairs to provide electrical signals containing information regarding edge position and direction of target rotation. The ATS19520 is intended for use with ferrous targets.

After proper power is applied to the sensor IC, it is capable of providing digital information that is representative of the magnetic features of a rotating target. The waveform diagrams in [Figure 5](#page-8-0) present the automatic translation of the target profiles, through their induced magnetic profiles, to the digital output signal of the sensor IC.

Figure 5: Magnetic Profile

The magnetic profile reflects the features of the target, allowing the sensor IC to present an accurate digital output.

Direction Detection

The sensor IC compares the relative phase of its two differential channels to determine which direction the target is moving. The relative switching order is used to determine the direction, which is communicated through the output protocol.

Data Protocol Description

When a target passes in front of the device (opposite the branded face of the package case), the ATS19520 generates an output pulse for each tooth of the target. Speed information is provided by the output pulse rate, while direction of target rotation is provided by the duration of the output pulses. The sensor IC can sense target movement in both the forward and reverse directions.

FORWARD ROTATION

As shown in panel A in [Figure 6](#page-8-1), when the target is rotating such that a tooth near the sensor $IC - of$ -Fxxxxxx variant – passes from pin 1 to pin 3, this is referred to as forward rotation. This direction is opposite for the -Rxxxxxx variant. Forward rotation is indicated by output pulse widths of $t_{w(FWD)}$.

REVERSE ROTATION

As shown in panel B in [Figure 6,](#page-8-1) when the target is rotating such that a tooth passes from pin 3 to pin 1, it is referred to as reverse rotation for the -Fxxxxxx variant. Reverse rotation is indicated by output pulse widths of $t_{w(REV)}$.

ASIL Protocol

The -xxxxxxx-A variant contains diagnostic circuitry that will continuously monitor occurrences of failure defects within the IC. Refer to [Figure 7](#page-9-0) for the output protocol of the ASIL Safe State after an internal defect has been detected. Error Protocol will result from faults which cause incorrect signal transmission (i.e., too few or too many output pulses).

Note: If a fault exists continuously, the device will attempt recovery indefinitely. Refer to the ATS19520 Safety Manual for additional details on the ASIL Safe State Output Protocol.

Figure 7: Output Protocol (ASIL Safe State)

POWER DERATING

The device must be operated below the maximum junction temperature of the device $(T_{J(max)})$. Under certain combinations of peak conditions, reliable operation may require derating supplied power or improving the heat dissipation properties of the application. This section presents a procedure for correlating factors affecting operating T_J . (Thermal data is also available on the Allegro website.)

The Package Thermal Resistance ($R_{\theta JA}$) is a figure of merit summarizing the ability of the application and the device to dissipate heat from the junction (die), through all paths to the ambient air. Its primary component is the Effective Thermal Conductivity (K) of the printed circuit board, including adjacent devices and traces. Radiation from the die through the device case (R_{BIC}) is relatively small component of $R_{\theta JA}$. Ambient air temperature (T_A) and air motion are significant external factors, damped by overmolding.

The effect of varying power levels (Power Dissipation, P_D), can be estimated. The following formulas represent the fundamental relationships used to estimate T_J , at P_D .

$$
P_D = V_{IN} \times I_{IN} \tag{1}
$$

$$
\Delta T = P_D \times R_{\theta J A} \tag{2}
$$

$$
T_J = T_A + \varDelta T \tag{3}
$$

For example, given common conditions such as: $T_A = 25^{\circ}C$, V_{CC} = 12 V, I_{CC} = 14 mA, and R_{θ JA} = 150°C/W, then:

$$
P_D = V_{CC} \times I_{CC} = 12 \ V \times 14 \ mA = 168 \ mW
$$

$$
\Delta T = P_D \times R_{0JA} = 168 \, mW \times 150^{\circ} \text{C/W} = 25.2^{\circ} \text{C}
$$
\n
$$
T_J = T_A + \Delta T = 25^{\circ} \text{C} + 25.2^{\circ} \text{C} = 50.2^{\circ} \text{C}
$$

A worst-case estimate, $P_{D(max)}$, represents the maximum allowable power level ($V_{CC(max)}$, $I_{CC(max)}$), without exceeding $T_{J(max)}$, at a selected $R_{\theta JA}$ and T_A

Example: Reliability for V_{CC} at $T_A = 150$ °C, package SN, using a single-layer PCB.

Observe the worst-case ratings for the device, specifically: $R_{\theta JA} = 150^{\circ}C/W$, $T_{J(max)} = 165^{\circ}C$, $V_{CC(max)} = 24$ V, and $I_{CC(avg)} =$ 14.6 mA. $I_{CC(avg)}$ is computed using $I_{CC(LOW)(max)}$ and $I_{CC(HIGH)}$ $_{\text{(max)}}$, with a duty cycle of 83% computed from $t_{\text{w(REV)(max)}}$ ontime at 4 kHz maximum operating frequency.

Calculate the maximum allowable power level, $P_{D(max)}$. First, invert equation 3:

$$
\Delta T_{max} = T_{J(max)} - T_A = 165^{\circ}C - 150^{\circ}C = 15^{\circ}C
$$

This provides the allowable increase to T_J resulting from internal power dissipation. Then, invert equation 2:

$$
P_{D(max)} = \Delta T_{max} \div R_{\theta JA} = 15\degree C \div 150\degree C/W = 100\text{ mW}
$$

Finally, invert equation 1 with respect to voltage:

 $V_{CC(est)} = P_{D(max)} \div I_{CC(avg)} = 100 \text{ mW} \div 14.6 \text{ mA} = 6.8 \text{ V}$

The result indicates that, at T_A , the application and device cannot dissipate adequate amounts of heat at operating voltages above 6.8 V at 150°C.

Compare $V_{CC(est)}$ to $V_{CC(max)}$. If $V_{CC(est)} \leq V_{CC(max)}$, then reliable operation between $V_{CC(est)}$ and $V_{CC(max)}$ requires enhanced $R_{\theta JA}$. If $V_{CC(est)} \ge V_{CC(max)}$, then operation between $V_{CC(est)}$ and $V_{\text{CC(max)}}$ is reliable under these conditions.

PACKAGE OUTLINE DRAWING

Figure 8: Package SN, 3-Pin SIP

Revision History

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